



FQP9N08

80V N-Channel MOSFET

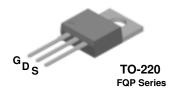
General Description

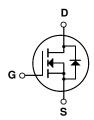
These N-Channel enhancement mode power field effect transistors are produced using Fairchild's proprietary, planar stripe, DMOS technology.

This advanced technology is especially tailored to minimize on-state resistance, provide superior switching performance, and withstand a high energy pulse in the avalanche and commutation modes. These devices are well suited for low voltage applications such as automotive, high efficiency switching for DC/DC converters, and DC motor control.

Features

- 9.3A, 80V, $R_{DS(on)}$ = 0.21 Ω @V_{GS} = 10 V Low gate charge (typical 5.9 nC)
- Low Crss (typical 13 pF)
- Fast switching
- 100% avalanche tested
- · Improved dv/dt capability
- 175°C maximum junction temperature rating





Absolute Maximum Ratings T_C = 25°C unless otherwise noted

Symbol	Parameter		FQP9N08	Units	
V _{DSS}	Drain-Source Voltage		80	V	
I _D	Drain Current - Continuous (T _C = 25°	C)	9.3	Α	
	- Continuous (T _C = 100°C)		6.57	Α	
I _{DM}	Drain Current - Pulsed	(Note 1)	37.2	Α	
V _{GSS}	Gate-Source Voltage		± 25	V	
E _{AS}	Single Pulsed Avalanche Energy	(Note 2)	55	mJ	
I _{AR}	Avalanche Current	(Note 1)	9.3	Α	
E _{AR}	Repetitive Avalanche Energy	(Note 1)	4.0	mJ	
dv/dt	Peak Diode Recovery dv/dt	(Note 3)	6.5	V/ns	
P _D	Power Dissipation (T _C = 25°C)		40	W	
	- Derate above 25°C		0.27	W/°C	
T_J , T_{STG}	Operating and Storage Temperature Range		-55 to +175	°C	
TL	Maximum lead temperature for soldering purposes, 1/8" from case for 5 seconds		300	°C	

Thermal Characteristics

Symbol	Parameter	Тур	Max	Units
$R_{\theta JC}$	Thermal Resistance, Junction-to-Case		3.75	°C/W
$R_{\theta CS}$	Thermal Resistance, Case-to-Sink	0.5		°C/W
$R_{\theta JA}$	Thermal Resistance, Junction-to-Ambient		62.5	°C/W

Symbol	Parameter	Test Conditions	s	Min	Тур	Max	Units
Off Cha	aracteristics						
BV _{DSS}	Drain-Source Breakdown Voltage	$V_{GS} = 0 \text{ V}, I_D = 250 \mu\text{A}$		80			٧
ΔBV _{DSS} / ΔT _J	Breakdown Voltage Temperature Coefficient	I _D = 250 μA, Referenced	to 25°C		0.08		V/°C
I _{DSS}	Zero Gate Voltage Drain Current	V _{DS} = 80 V, V _{GS} = 0 V				1	μΑ
		V _{DS} = 64 V, T _C = 150°C				10	μΑ
I _{GSSF}	Gate-Body Leakage Current, Forward	$V_{GS} = 25 \text{ V}, V_{DS} = 0 \text{ V}$				100	nA
I _{GSSR}	Gate-Body Leakage Current, Reverse	$V_{GS} = -25 \text{ V}, V_{DS} = 0 \text{ V}$				-100	nA
On Cha	racteristics						
V _{GS(th)}	Gate Threshold Voltage	$V_{DS} = V_{GS}, I_D = 250 \mu\text{A}$		2.0		4.0	V
R _{DS(on)}	Static Drain-Source On-Resistance	V _{GS} = 10 V, I _D = 4.65 A			0.16	0.21	Ω
9 _{FS}	Forward Transconductance	V _{DS} = 30 V, I _D = 4.65 A	(Note 4)		3.6		S
C _{iss}	Input Capacitance Output Capacitance	$V_{DS} = 25 \text{ V}, V_{GS} = 0 \text{ V},$ f = 1.0 MHz			190 70	250 90	pF pF
C _{rss}	Reverse Transfer Capacitance				13	17	pF
Switchi	ing Characteristics						
t _{d(on)}	Turn-On Delay Time	$V_{DD} = 40 \text{ V}, I_D = 9.3 \text{ A},$ $R_G = 25 \Omega$ (Note 4, 5)			2.8	15	ns
t _r	Turn-On Rise Time				28	65	ns
$t_{d(off)}$	Turn-Off Delay Time				9	28	ns
t _f	Turn-Off Fall Time				17	45	ns
Q_g	Total Gate Charge	$V_{DS} = 64 \text{ V}, I_{D} = 9.3 \text{ A},$			5.9	7.7	nC
Q_{gs}	Gate-Source Charge	V _{GS} = 10 V (Note 4, 5			1.5	1	nC
Q_{gd}	Gate-Drain Charge				2.6		nC
Drain-S	Source Diode Characteristics ar	nd Maximum Rating	s				
I _S	Maximum Continuous Drain-Source Diode Forward Current				9.3	Α	
I _{SM}	Maximum Pulsed Drain-Source Diode Forward Current				37.2	Α	
V _{SD}	Drain-Source Diode Forward Voltage	V _{GS} = 0 V, I _S = 9.3 A				1.5	V
t _{rr}	Reverse Recovery Time	$V_{GS} = 0 \text{ V}, I_{S} = 9.3 \text{ A},$			50		ns
Q _{rr}	Reverse Recovery Charge	$dI_{F} / dt = 100 \text{ A/}\mu\text{s}$ (Note 4)			70		nC

- $\label{eq:Notes:1} \begin{array}{ll} \textbf{Notes:} \\ 1. \ \text{Repetitive Rating: Pulse width limited by maximum junction temperature} \\ 2. \ L = 0.87\text{mH}, \ l_{AS} = 9.3\text{A}, \ V_{DD} = 25\text{V}, \ R_G = 25\ \Omega, \ \text{Starting} \quad T_J = 25^{\circ}\text{C} \\ 3. \ l_{SD} \leq 9.3\text{A}, \ \text{di/dt} \leq 300\text{A/µs}, \ V_{DD} \leq B\text{V}_{DSS}, \ \text{Starting} \quad T_J = 25^{\circ}\text{C} \\ 4. \ \text{Pulse Test: Pulse width} \leq 300\text{µs}, \ \text{Duty cycle} \leq 2\% \\ 5. \ \text{Essentially independent of operating temperature} \end{array}$

Typical Characteristics

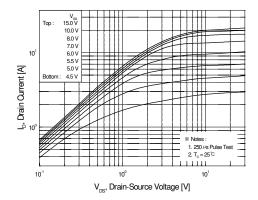


Figure 1. On-Region Characteristics

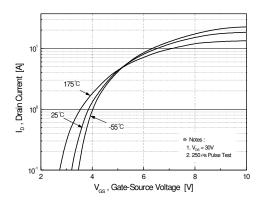


Figure 2. Transfer Characteristics

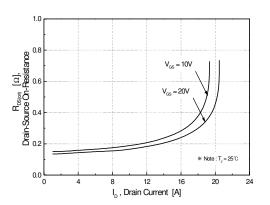


Figure 3. On-Resistance Variation vs. Drain Current and Gate Voltage

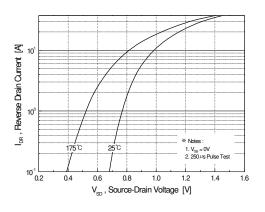


Figure 4. Body Diode Forward Voltage Variation vs. Source Current and Temperature

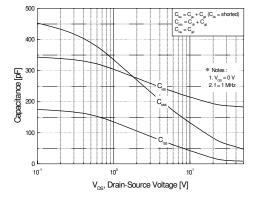


Figure 5. Capacitance Characteristics

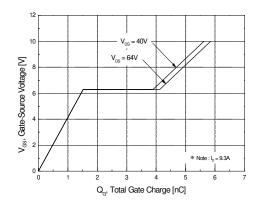
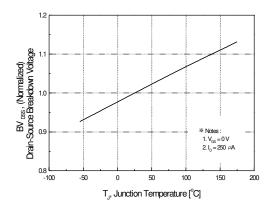


Figure 6. Gate Charge Characteristics

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Typical Characteristics (Continued)



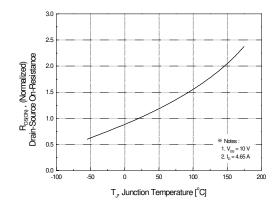
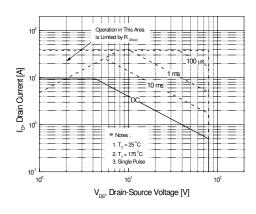


Figure 7. Breakdown Voltage Variation vs. Temperature

Figure 8. On-Resistance Variation vs. Temperature



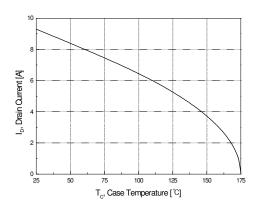


Figure 9. Maximum Safe Operating Area

Figure 10. Maximum Drain Current vs. Case Temperature

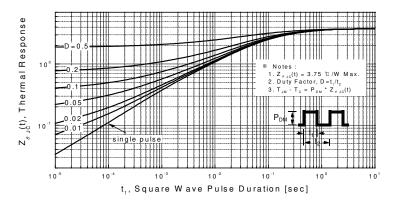
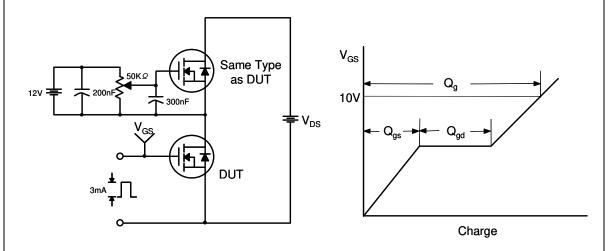


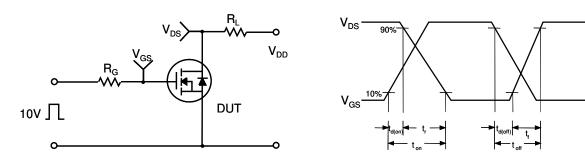
Figure 11. Transient Thermal Response Curve

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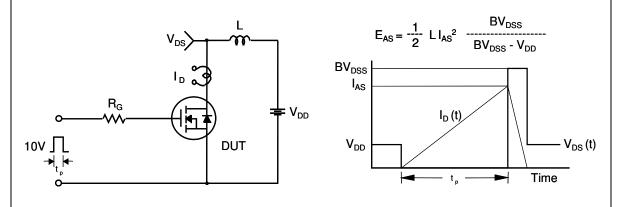
Gate Charge Test Circuit & Waveform



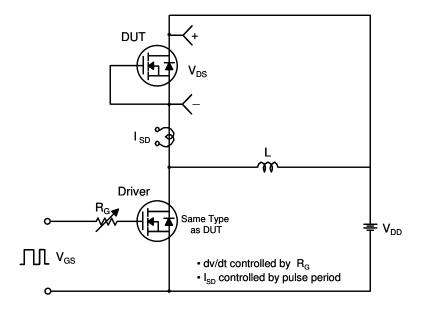
Resistive Switching Test Circuit & Waveforms

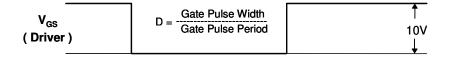


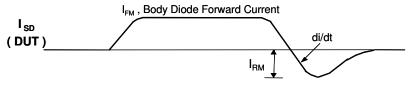
Unclamped Inductive Switching Test Circuit & Waveforms



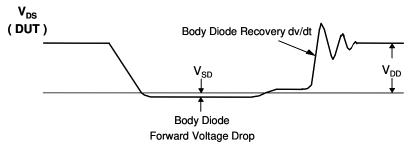
Peak Diode Recovery dv/dt Test Circuit & Waveforms

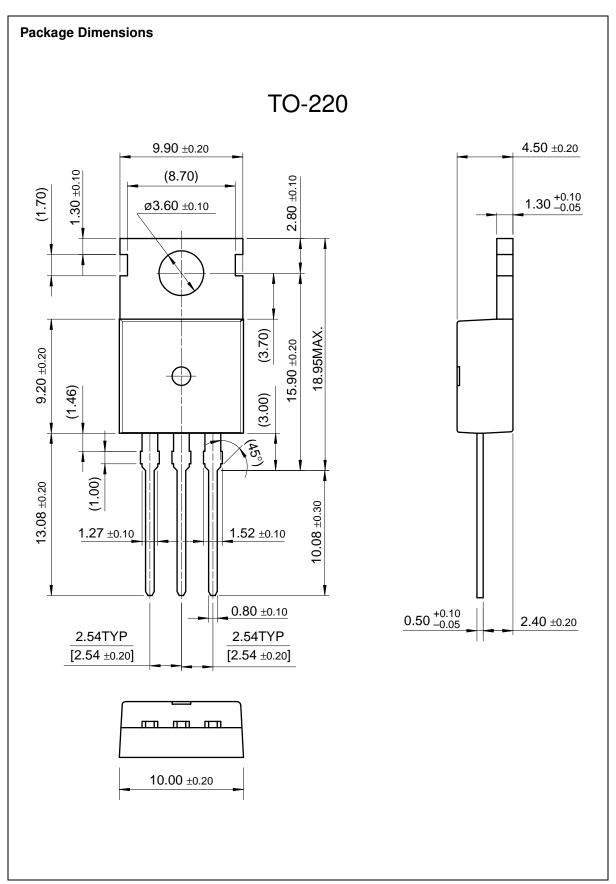






Body Diode Reverse Current





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